

**Search Notes**

Application/Control No.

10/804,655

Examiner

Jinhee J. Lee

Applicant(s)/Patent under  
Reexamination

SMITH ET AL.

Art Unit

2831

**SEARCHED**

Class	Subclass	Date	Examiner
174	113R	3/21/2005	LEE
	110FC		
	126.1		
	119R		
	110R		
	100		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
174	as above	3/21/2005	LEE

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR